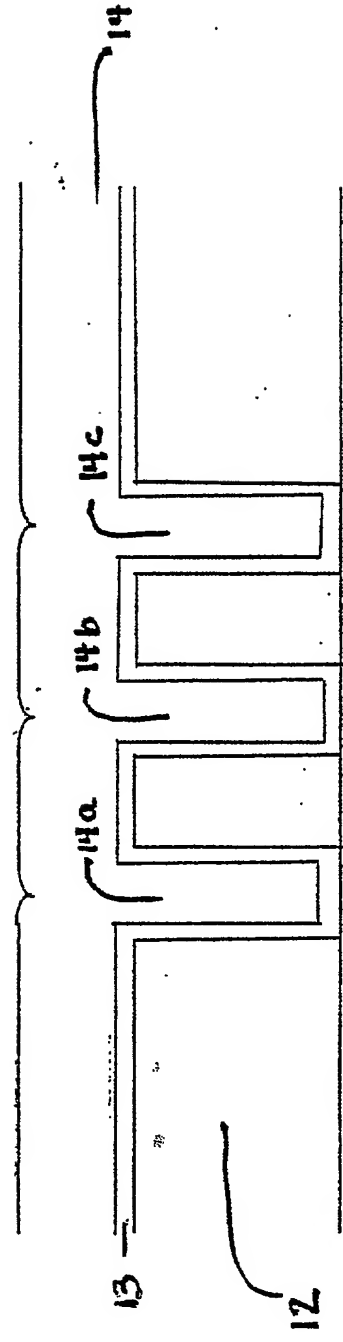


10



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FIG. 1

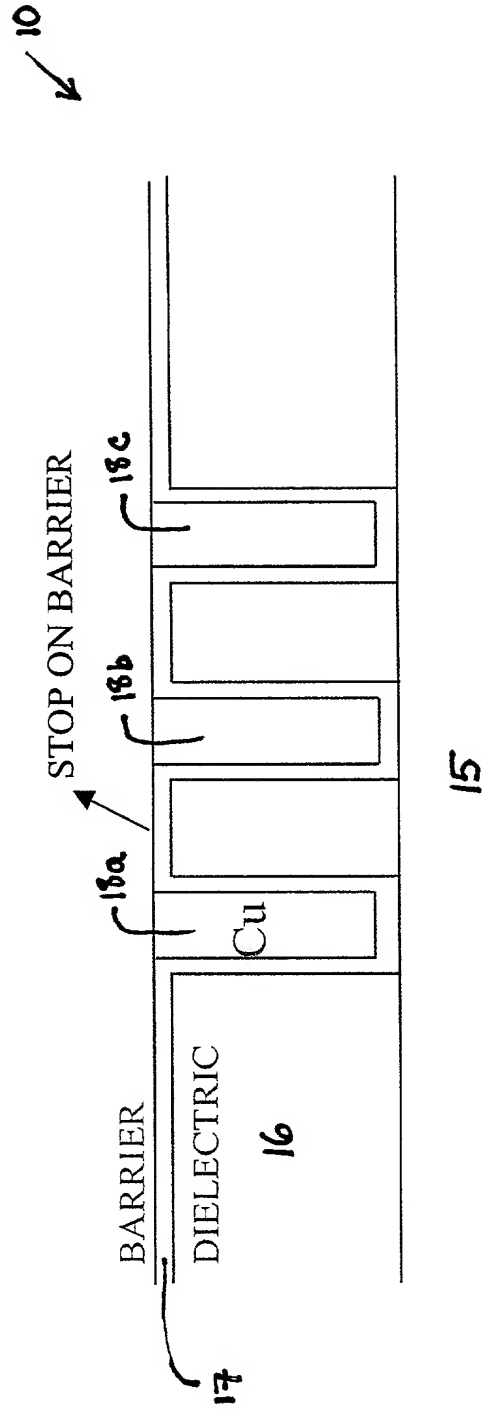


FIG. 2

FIG. 3 is a cross-sectional view of a semiconductor device in accordance with the present invention.

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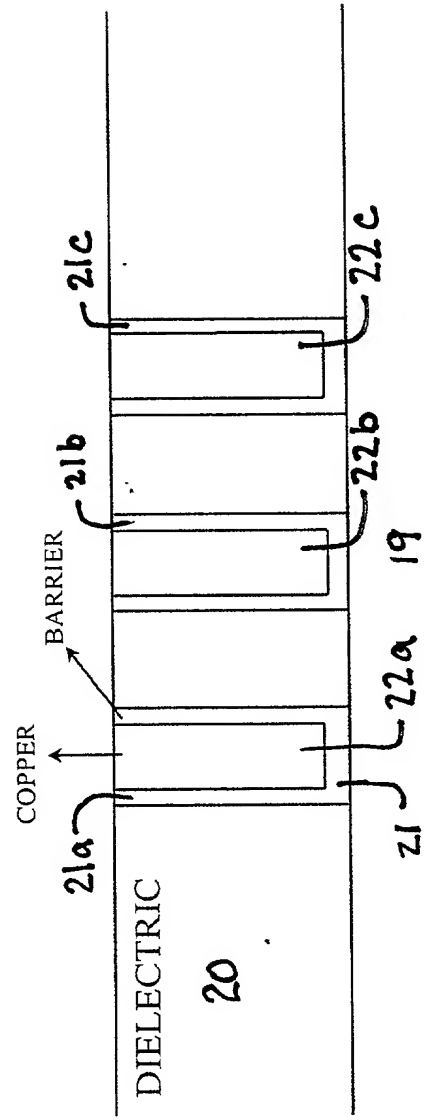


FIG. 3

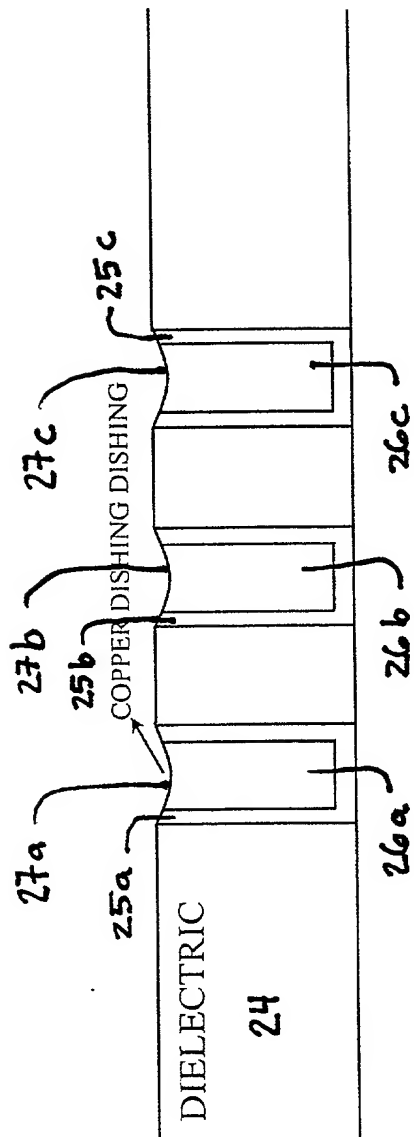


FIG. 4

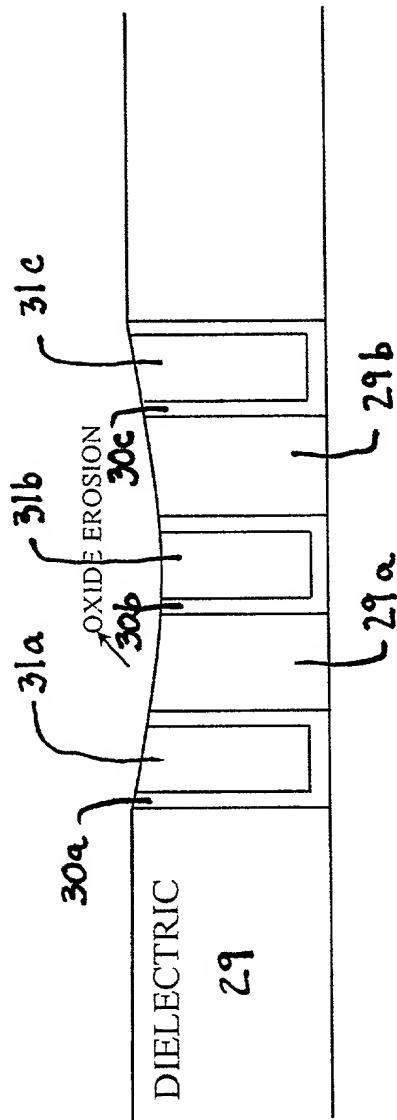


FIG. 5

Spherical Precipitated Silica-13 NM

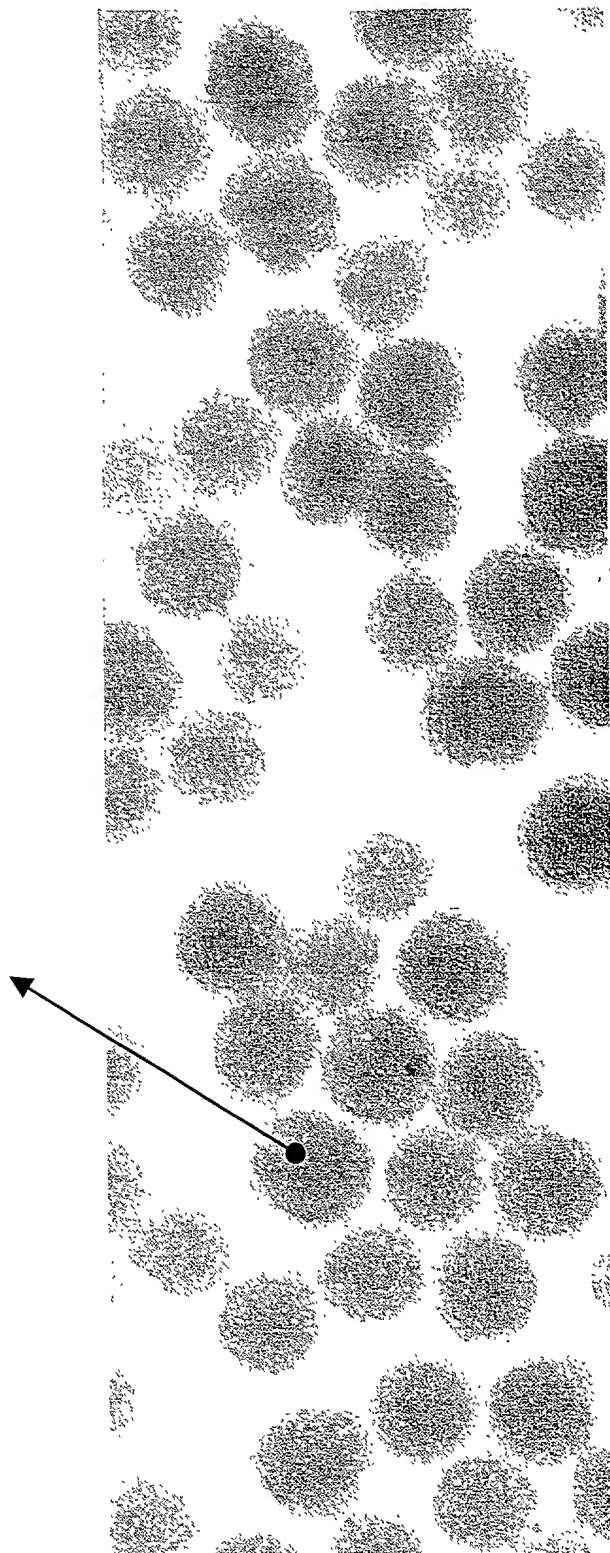


FIG. 6

COULTER N4 PLUS PARTICLE ANALYSIS (13 nm COLLOIDAL SILICA)

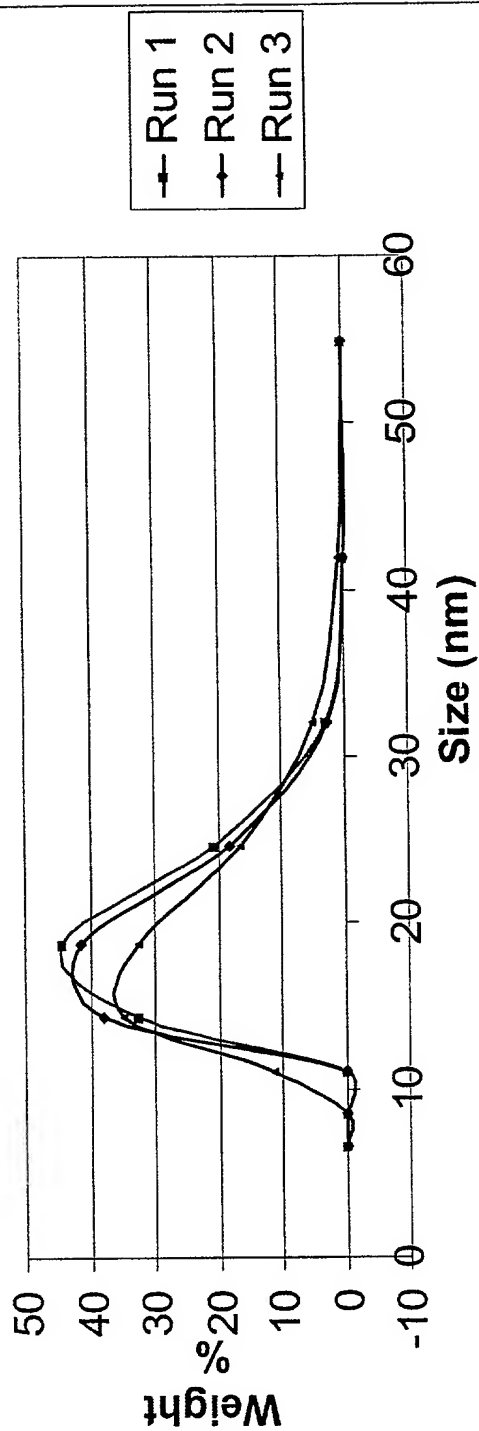


FIG. 7